IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Kwang Su Choe, et al. Examiner: Unknown

Serial No.: 10/674,647 Art Unit: 1762

Filed: September 30, 2003 Docket: YOR920030293US1 (16818)

Dated: October 11, 2007

For: THIN BURIED OXIDES BY LOW-DOSE

OXYGEN IMPLANTATION INTO MODIFIED

SILICON

Confirmation No: 4796

Mailstop Amendment Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

DECLARATION PURSUANT TO 37 C.F.R. 1.131

Sir:

We, Kwang Su Choe, Keith E. Fogel, Siegfried L. Maurer, Ryan M. Mitchell and Devendra K. Sadana hereby declare that:

- We are co-inventors of the subject matter described and claimed in the above-identified
 patent application.
- 2. Prior to December 20, 2002, which is the effective filing date of U.S. Patent No. 6,800,518 to Bendernagle et al., we have conceived and reduced to practice a semiconductor structure including a buried oxide layer in accordance with claims 1,23 and 24 of the above-identified patent application.
- As evidence of conception and reduction to practice referred to in paragraph 2 above, we
 have annexed hereto Exhibit A and Exhibit B. Exhibit A is a true copy of IBM invention

disclosure YOR820010417, which was created prior to December 20, 2002. Exhibit B is a true copy of IBM invention disclosure YOR820010812, which was also created prior to December 20, 2002. Each of Exhibit A and Exhibit B teaches the basic features of the invention as claimed in claim 1, claim 23 and claim 24, including in particular the claimed oxygen implant dose of less than 10E17 oxygen ions per square centimeter. Electron Micrographs attached are part of Exhibit B, all names and dates have been redacted in the preparation of this declaration.

4. We do hereby declare that all statements made herein of our own knowledge are true, and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment or both under 18 U.S.C. § 1001, and that such willful statements may jeopardize the validity or enforceability of the patent.

Dated	Kwang Choe
Dated	Keith E. Fogel
Dated	Siegfried L. Maurer
Dated	Ryan M. Mitchell
Dated	Devendra K. Sadana



Disclosure YOR8-2001-0417

Prepared for and/or by an IBM Attorney - IBM Confidential

" A"

Required fields are marked with the asterisk (*) and must be filled in to complete the form .

*Title of disclosure (in English) A near zero oxygen dose SIMOX

Summary

denotes primary cont				_			
Inventor Name			Inventor Serial	Div/Dept	Inventor Phone	Manager Name	
nventors with a Bli inventors:	ue Page	s entry					
PVT Score		71					
Technology Code							
Lab							
Incentive Program							
*Owning Division	select	RES					
Submitted Date	301601						
Professional IDT Team	select						
*Functional Area Attorney/Patent	select	(700) 700	Isaac-Syste	ems, Techno	logy & Scienc	е	
*Processing Location		Yorktown					
Docket Family		YOR9-20	03-0293				
Merged Disclosures		YOR8-20	01-0812				
Final Deadline Reason							
Final Deadline			11 110				
Status		Final De	clsion (File				

inventors without a Blue Pages entry

IDT Selection

Allomey/Patent Professional IDT Team

//

Response Due to iP&L

*Main Idea

- Describe your invention, stating the problem solved (if appropriate), and indicating the advantages of using the invention.
- using the inventors.

 To produce low cost SOI substrate by anodic etching epitaxial silicon growth and oxidation. First, select a silicon substrate and form a layer of porous silicon on the upper surface. Then, treat the very top surface of the porous silicon with hydrogen to form a layer of single crystal silicon. Then form an epitaxial silicon layer of a desired thickness. Heat the structure in an oxidizing ambient to induce internal thermal oxidation of the porous region to create a buried oxide layer and at the same time a SOI structure.
- How does the invention solve the problem or achieve an advantage, (a description of "the invention", No ion implicate time of problems in proceedings in proceedings.

No ion implantation or bonding is necessary to form an SOI substrate. A wide range of the insulator thickness can be formed for example in the range from 100 A to 2 microns.

- 3. If the same advantage or problem has been identified by others (inside/outside IBM), how have those others solved it and does your solution differ and why is it better?
 Current practice is to use oxygen implantation or bonding to create SOI.
- 4. If the invention is implemented in a product or prototype, include technical details, purpose, disclosure details to others and the date of that implementation.

Critical Questions (Questions 1-9 must be answered in English)	
*Question 1	
On what date was the invention workable? *lease format the date (Workable means i.e. when you know that your design will solve the problem)	as MM/DD/YYYY
*Question 2	
Is there any planned or actual publication or disclosure of your invention to anyone outside IBM?	O Yes ● No
If yes, Enter the name of each publication or patent and the date published bell Publication/Patent:	ow.
Date Published or Issued: Are you aware of any publications	
Are you aware of any publications, products or patents that relate to this invention?	• Yes
If yes, Enter the name of each publication or patent and the date published belo	O No
Publication/Patent: Cannon patent on using porous silicon to make SOI wafers (Yonehara et al.). Date Published or Issued: 3 or 4 years ago.	W.
Question 3	
Has the subject matter of the invention or a product incorporating the invention been sold, used internally in manufacturing, announced for sale, or included in proposal?	O Yes ● No
is a sale, use in manufacturing, product announcement, or proposal planned?	a a
	C Yes
If Yes, identify the product if known and in the control of	● Na
If Yes, Identify the product if known and indicate the date or planned date of sale proposal and to whom the sale, announcement or proposal has been or will be in Product:	, announcements, or nade.

Pogo 2

Code Name: Date:

*Question 4 Was the subject matter of your invention or a product incorporating your invention used in public, e.g., outside IBM or in the presence of non-IBMers If yes, give a date Place for	O Yes ● No
If yes, give a date. Please format the date as MM/DD/YYYY	<i>(</i>
*Question 5	
Have you ever discussed your invention with others not employed at IBM?	O Yes
If yes, identify individuals and date discussed. Fill in the text area with the for names of the individuals, the employer, date discussed, under CDA, and CD	lowing information, the A #.
*Question 6	
Was the invention, in any way, started or developed under a government contract or project?	○ Yes ● No
if Yes, enter the contract number	O Not sure
Question 7	
Was the invention made in the course of any alliance, joint development or of contract activities?	O Yes her ● No
If Yes, enter the following:	O Not Sure
Name of Alliance, Contractor or Joint Develop	er
Contract ID number	
Relationship contact name	
Relationship contact E-mail	
Relationship contact phone	
Question 8	
lave you, or any of the other inventors, submitted this same invention lisciosure or similar invention disclosure previously?	○ Yes • No
Yes, please provide disclosure number below:	
luestion 9	
re you, or any of the other inventors, aware of any related inventions sclosures submitted by anyone in IBM previously?	O Yes ● No
Yes, please provide the docket or disclosure number or any other identifying	information below:

maguyi-0417 A near zero oxygen dose SIMOX - continued
Manufacturers of enterprise servers
Manufacturers of entry servers
Manufacturers of workstations
Manufacturers of PC's
Non-computer manufacturers
Developers of operating systems
Developers of networking software
Developers of application software
Integrated solution providers
Service providers
Other (Please specify below)
semiconductor wafer suppliers
Question 11
if the invention relates to a product or service that is outside the scope of your business unit, please
recommend IBM business unit(s), IBM location(s) or individual(s) within IBM that you think would provide a good evaluation of your invention:
*Patent Value Tool (Optional - this may be used by the inventor and attorney to assist with the evalu
(The Patent Value tool can be used by the inventor(s) to determine the potential licensing value of your invention.)
Market
*Question 1: What is the anticipated annual market size (in dollars) that will be captured by your invention?
Greater than \$5B
Reason(s) for above Answer:
Claims
*Question 1: How new is the technical field?
Reason(s) for above Answer:
*Question 2: How control is the investigation
*Question 2: How central is the invention to the product(s) which might be expected to contain the
Entire Product
Reason(s) for above Answer:
Table (6) for above Allawer.
*Question 3: What is the scope of the claim?
Broad
Reason(s) for above Answer:
· · · · · · · · · · · · · · · · · · ·
Portfolio Need
Question 1: What are the portfolio needs in the area of your invention?
Listed III PPIVI Needs
Reason(s) for above Answer: PPM 100 A4
Exploitation & Enforcement
Question 1: How easily can the use of the invention by a competitor be detected?
THE POINT
Reason(s) for above Answer:
Question 2: How easily can the use of the invention be avoided by a competitor?

With much work

Reason(s) for above Answer: the process is low cost

Business Value

*Question 1: What percentage of the companies producing products in the field of this invention might

Broadly cloned

Reason(s) for above Answer:

*Question 2: What is the value of this patent to current or anticipated Alliance Activity between IBM and High value

Reason(s) for above Answer:

*Question 3: What is the value of this patent to current or anticipated Technology Transfer Activity between IBM and other companies? High value

Reason(s) for above Answer:

*Question 4: Does it result in prestige to IBM?

Industry wide

Reason(s) for above Answer:

Final Decision

This decision was entered by Kathy Cognatello/Watson/IBM on:

Decision: File		
PPM Area: 100 - Solid State Technologies	Status: N/A	
Date of Final Decision	Attorney Rating: 2	
Date of Final Decision		

Additional filing information

Planned Filing date:

Filing comments:

Additional decision comments

Final Decison History

Entered on 5

Merged Disclosures: YOR8-2001-0812

Post Disclosure Text & Drawings

To add additional information related to this disclosure once it has been submitted, click the action button below and a new document will be opened for you to enter the new information. To view existing post disclosure information, double-click on the item in the list below (if there has been additional information entered), and the document will open for you to view. Date entered Post disclosure information (comments and drawings)

Form Revised

. 400

Disclosure YOR8-2001-0812 Prepared for and/or by an IBM Attorney - IBM Confidential

Required fields are marked with the asterisk ($\overset{\star}{}$) and must be filled in to complete the form .

*Title of disclosure (in English)

Thin Buried Oxides by Oxygen Implantation into Modified Silicon

Summary

Status	
Final Deadline	Final Decision (File/Merge)
Final Deadline	
Reason	
Primary	
Disclosure	YOR8-2001-0417
Docket Family	YOR9-2003-0293
*Processing	
Location	Yorktown
*Functional Area	select (700) 700 Isaac-Systems, Technology & Science
Attorney/Patent	Science Systems, recliniology & Science
Professional	
IDT Team	select
Submitted Date	
*Owning Division	select RES
Incentive	
Program	
Lab	
,Technology	
Code	
PVT Score	71
Wentors with a Blu	In Pages and

inventors with a Blue Pages entry Immont....

Inventor Name	Inventor Serial Div/Dept	Inventor Phone	Manager Name	
> denotes primary contact				

Inventors without a Blue Pages entry

IDT Solection

Allorney/Patent

Professional IDT Team Response Due to IP&L

*Main Idea

1. Describe your invention, stating the problem solved (if appropriate), and indicating the advantages of

Thin continuous buried oxides (< 300A) are extremely difficult to fabricate by convetional methods, such as SIMOX or wafer bonding. There is no known demonstration of such layers in prior art to our knowledge. High sufrace energy associated with the formation of such oxides tend to make them ball up during their fabrication resulting in a discontinous and fragmented oxide layer.

The present invention overcomes this difficulty by a novel method which includes the following steps: (i) treating the surface of a Si substrate by a process which creates high concentration of vacancies and voids in the surface region, (ii) growing a single crystal Si layer above the treated surface, (iii) implanting oxygen into the novel structure, and (iv) annealing the implanted samples at high temperatures (>1100C). Continuus buried oxide layers of < 500A can be created controllably by this method.

We now describe details of each step. For step (i) anodic oxidation of Si is performed in a HF(49%) or HF/ethanol electrolyte such that a very low density porous-Si, or highly vacancy rich Si layer is created. The thickness and porosity of this layer can be controlled by a number of parameters, such as the toal current flow during anodic oxidation/etching, time, HF concetration, HF/ethanol ratio, Si substrate doping and doping concentration etc. For step (ii) conventional SI epitaxial reactors such as those made by ASM or Applied Material can be used. For step (iii) a conventional or SiMOX implanter can be used. Typical oxyge implant dose should be < 1E17 cm-2. For step (iv) convetional furnaces or those used for SIMOX

Figures below show how the invention has been reduced into practice. The first micrograph in each case shows the region which was untreated. It is clear that the present invention has a profound effect on the formation a continuous and thin buried oxide





Z5X-063001A1-203.ti Z5X-063001A1-200.ti

Z5X-200 shows discontinous buried oxide. This region did not receive any porous-Si treatment. Z5X-2003 shows a thin and continous buried oxide. This region did receive the porous-Si treatment.



ICX-063001A1-203.t

ICX-203 shows a thin and continous buried oxide. This region did receive the porous-Si treatment. Oxygen dose in this case is 1E17 cm-2 at 210 keV

Major Claims

- A method to form ultrathin buried oxide layers by implating oxygen into a Si substrate containing a buried vacancy-rich region, and annealing the said structure at temperatures of > 1100C.
- Controlling the oxide thickness by the implanted oxygen dose.

Controlling the oxide thickness by internal thermal oxidation.

2. How does the invention solve the problem or achieve an advantage (a description of "the invention", including figures inline as appropriate)?

The invenion opens up new frontiers in Si technology for multiple applications, such as, buried ground plane MOSFETs, Double gate MOSFETs etc. The process is quite manufacturable and therefore can be

- 3. If the same advantage or problem has been identified by others (Inside/outside IBM), how have those others solved it and does your solution differ and why is it better? The others have not yet been able to solve this problem.
- 4. If the invention is implemented in a product or prototype, include technical details, purpose, disclosure details to others and the date of that implementation. CMOS 11S and beyond technology generation

On what date was the invention workable? Please format the date (Workable means i.e. when you know that your scales will be a long to the control of the con	e as MM/DD/YYYY
(Workable means i.e. when you know that your design will solve the problem)	
*Question 2	
	O Yes
Is there any planned or actual publication or disclosure of your invention to anyone outside IBM?	● No
If yes, Enter the name of each publication or patent and the date published be Publication/Patent: Date Published or Issued:	low.
Are you aware of any publications, products or patents that relate to this	O Yes
mroman;	_
If yes, Enter the name of each publication or patent and the date published bel Publication/Patent: Date Published or issued:	low.
Question 3	
Has the subject matter of the invention or a product incorporating the invention	O Yes
proposal?	● No i a
s a sale, use in manufacturing, product announcement, or proposal planned?	O Yes
f Yes, identify the product if known and indicate the date or planned date of sal proposal and to whom the sale, annuncement or proposal has been	
proposal and to whom the sale, announcement or proposal has been or will be Product Product Product Code Name: Date: To Whom:	le, announcements, or made.
f more then one was and	
more than one, use cut and paste and append as necessary in the field provid	ded.
uestion 4	Ou
Vas the subject matter of your invention or a product incorporating your ivention used in public, e.g., outside IBM or in the presence of non-IBMers?	O Yes
	● No

Question 5	
Have you ever discussed your invention with others not employed at IBM?	O Yes ■ No
If yes, identify individuals and date discussed. Fill in the text area with the for names of the individuals, the employer, date discussed, under CDA, and Cl	
Question 6	
Was the invention, in any way, started or developed under a government contract or project?	O Yes ● No
If Yes, enter the contract number	O Not sure
Question 7	
Was the invention made in the course of any alliance, joint development or contract activities?	O Yes
f Yes, enter the following:	O Not Sure
Name of Alliance, Contractor or Joint Develo	ner
Contract ID number	
Relationship contact name	
Relationship contact E-mail	
Relationship contact phone	
uestion 8	
ave you, or any of the other inventors, submitted this same invention sclosure or similar invention disclosure previously?	O Yes ● No
Yes, please provide disclosure number below:	
uestion 9	· · · · · · · · · · · · · · · · · · ·
e you, or any of the other inventors, aware of any related inventions	O Yes ■ No
sciosures submitted by anyone in IBM previously? Yes, please provide the docket or disclosure number or any other identifying	
	information below:
estion 10	

48-2001-0812 Thin Buried Oxides by Oxygen implantation into Modified Silicon - continued
Manufacturers of enterprise servers
Manufacturers of entry servers
Manufacturers of workstations
Manufacturers of PC's
□ Non-computer manufacturers
Developers of operating systems
☐ Developers of networking software ☐ Developers of application software
☐ Integrated solution providers
Service providers
Other (Please specify below)
Outed (Liegos sharily ballow)
Question 11
If the invention relates to a product or service that is outside the scope of your business unit, please recommend IBM business unit(s), IBM location(s) or individual(s) within IBM that you think would provide a good evaluation of your invention:
Patent Value Tool (Optional - this may be used by the inventor and attorney to assist with the evalu
(The Patent Value tool can be used by the inventor(s) to determine the potential licensing value of your invention.) Market
*Question 1: What is the anticipated annual market size (In dollars) that will be captured by your invention?
Greater than \$5B Reason(s) for above Answer:
Claims *Question 1: How new is the technical field?
Future
Reason(s) for above Answer:
*Question 2: How central is the invention to the product(s) which might be expected to contain the invention? Main
Reason(s) for above Answer:
*Question 3: What is the scope of the claim? Fundamental
Reason(s) for above Answer:
Portfolio Need
*Question 1: What are the portfollo needs in the area of your invention? Listed in PPM Needs Reason(s) for above Answer:
Exploitation & Enforcement Question 1: How easily can the use of the invention by a competitor be detected? With work Ronson(s) for above Answer:
Question 2: How easily can the use of the invention be avoided by a competitor?

Page 5

Wilh much work

(cason(s) for above Answer:

Business Value

*Question 1: What percentage of the companies producing products in the field of this invention might use this invention?

Broadly cloned

Reason(s) for above Answer:

*Question 2: What is the value of this patent to current or anticipated Alliance Activity between IBM and other companies?

High value

Reason(s) for above Answer:

*Question 3: What is the value of this patent to current or anticipated Technology Transfer Activity between IBM and other companies?

High value

Reason(s) for above Answer:

*Question 4: Does it result in prestige to IBM?

Industry wide

Reason(s) for above Answer:

Final Decision

This decision was entered by

Decision: File/Merge Status: N/A
Merged with disclosure number : YOR8-2001-0417

Date of Final Decision :

Additional filing information

Planned Filing date:

Filing comments:

Additional decision comments

Final Decison History

Entered on File/Merged with: YOR8-2001-0417 Docket(s) Family: YOR920030293

Post Disclosure Text & Drawings

To add additional information related to this disclosure once it has been submitted, click the action button below and a new document will be opened for you to enter the new information. To view existing post disclosure information, double-click on the item in the list below (if there has been additional information entered), and the document will open for you to view.

Date entered Post disclosure Information (comments and drawings)

Form Revised 09/01/02)

H 3 = 124 nm

H2 = 36 nm

H 1 = 1.368 µm

ICX-063001A1-2

Mag = 21.54 K X

200nm

WD= EHT = 10.00 KV 2 mm

File Name = ICX-063001A1-203.tif

Date

POROUS AREA

H 1 = 12 nm

Z5X-063001A1-2

EHT = 10.00 kV WD = 3 mm Date File Name = Z5X-063001A1-203.tif

Mag = 46.31 K X

Toon

NON-POUROUS SIDE

H 2 = 76 nm

Z5X-063001A1-2

Mag = 30.71 K X

300nm

WD= 3 mm

EHT = 10.00 KV

Date File Name = Z5X-063001A1-200.tif